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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

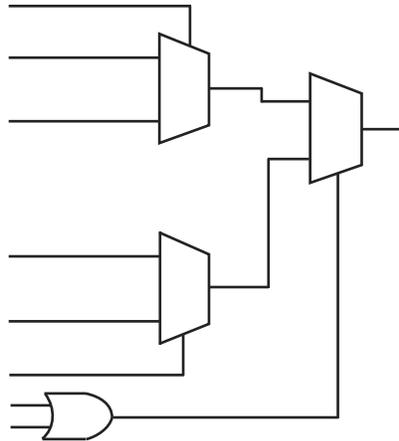
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	72
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-pl84m

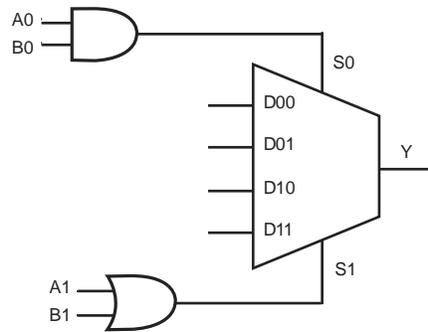
Figure 51	BG272	145
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Figure 53	CQ172	158

Figure 2 • 42MX C-Module Implementation



The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

Figure 3 • 42MX C-Module Implementation



Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • Voltage Support of MX Devices

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

3. All outputs unloaded. All inputs = VCC/VCCI or GND

3.8 3.3 V Operating Conditions

The following table shows 3.3 V operating conditions.

Table 16 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	−0.5 to +7.0	V
VI	Input Voltage	−0.5 to VCC + 0.5	V
VO	Output Voltage	−0.5 to VCC + 0.5	V
t _{STG}	Storage Temperature	−65 to + 150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 17 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	−0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	−0.5 to +7.0	V
VI	Input Voltage	−0.5 to VCCI+0.5	V
VO	Output Voltage	−0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	−65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 18 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	−40 to +85	−55 to +125	°C
VCC (40MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
VCCA (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V
VCCI (42MX)	3.0 to 3.6	3.0 to 3.6	3.0 to 3.6	V

Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

All the following tables show various specifications and operating conditions of 40MX and 42MX FPGAs.

3.9.1 Mixed 5.0V/3.3V Electrical Specifications

Table 22 • Mixed 5.0V/3.3V Electrical Specifications

Symbol	Parameter	Commercial		Commercial –F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					2.4		2.4		V
VOL ¹	IOL = 10 mA	0.5		0.5						V
	IOL = 6 mA					0.4		0.4		V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH ²		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V		–10		–10		–10		–10	μA
IH	VIN = 2.7 V		–10		–10		–10		–10	μA
Input Transition Time, T _R and T _F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ³	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low Power Mode Standby Current			0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0	mA
I/O I/O source sink current	Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCCI = min.
2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
3. All outputs unloaded. All inputs = VCCI or GND

3.9.2 Output Drive Characteristics for 5.0 V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

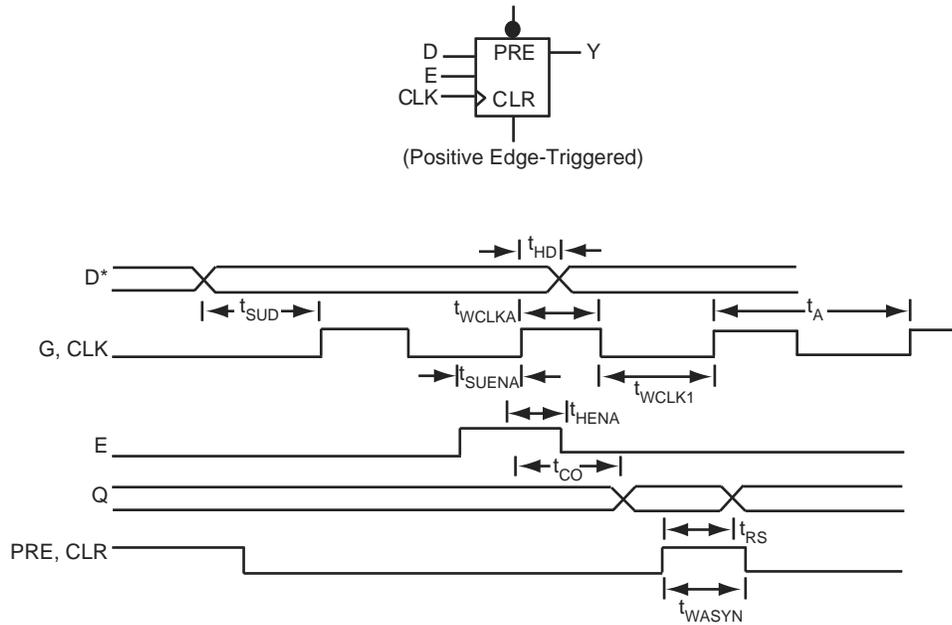
Table 23 • DC Specification (5.0 V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
VCCI	Supply Voltage for I/Os		4.75	5.25	4.75	5.25 ²	V
VIH ³	Input High Voltage		2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage		–0.5	0.8	–0.3	0.8	V
I _{IH}	Input High Leakage Current	VIN = 2.7 V		70	—	10	μA
I _{IL}	Input Low Leakage Current	VIN=0.5 V		–70	—	–10	μA
VOH	Output High Voltage	I _O UT = –2 mA I _O UT = –6 mA	2.4		3.84		V
VOL	Output Low Voltage	I _O UT = 3 mA, 6 mA		0.55	—	0.33	V

3.10.2 Sequential Module Timing Characteristics

The following figure shows sequential module timing characteristics.

Figure 25 • Flip-Flops and Latches



Note: *D represents all data functions involving A, B, and S for multiplexed flip-flops.

3.10.3 Sequential Timing Characteristics

The following figures show sequential timing characteristics.

Figure 26 • Input Buffer Latches

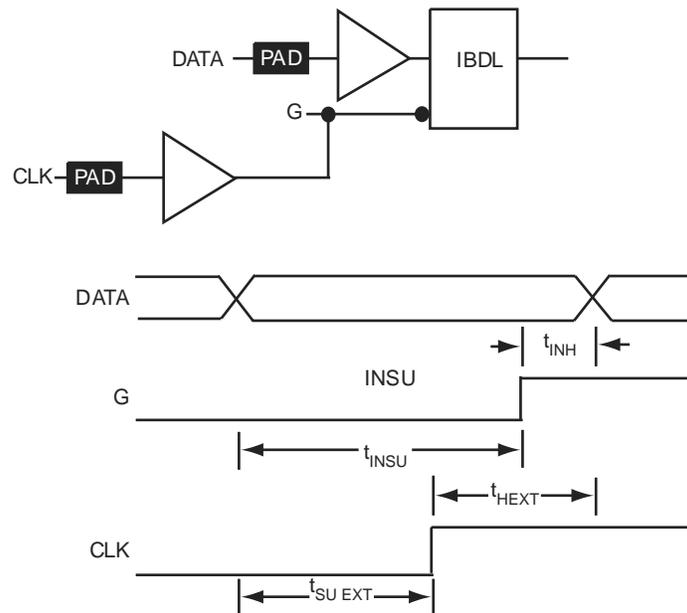
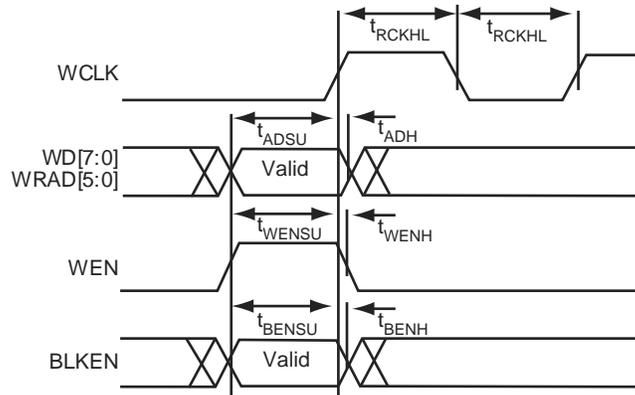
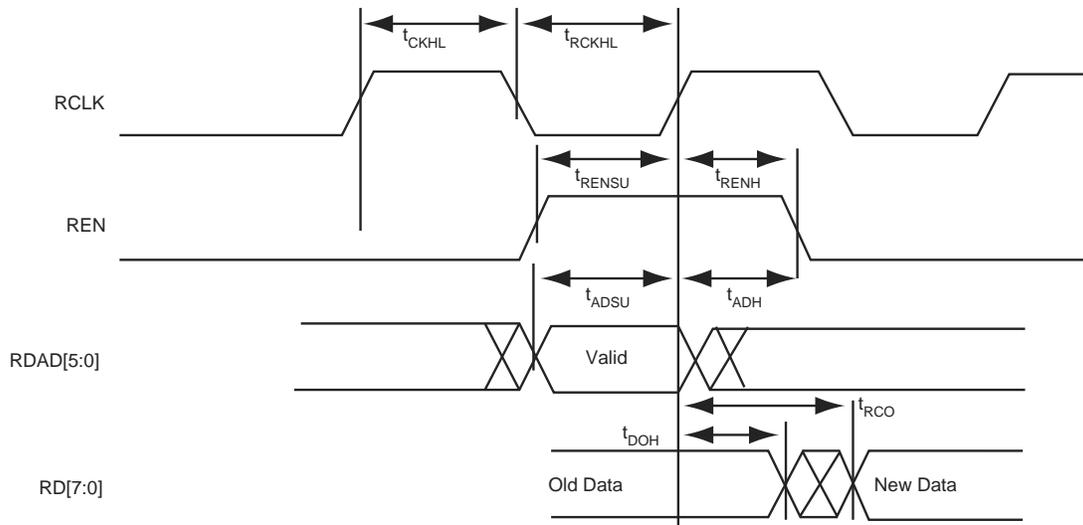


Figure 30 • 42MX SRAM Write Operation



Note: Identical timing for falling edge clock

Figure 31 • 42MX SRAM Synchronous Read Operation



Note: Identical timing for falling edge clock

Figure 32 • 42MX SRAM Asynchronous Read Operation—Type 1 (Read Address Controlled)

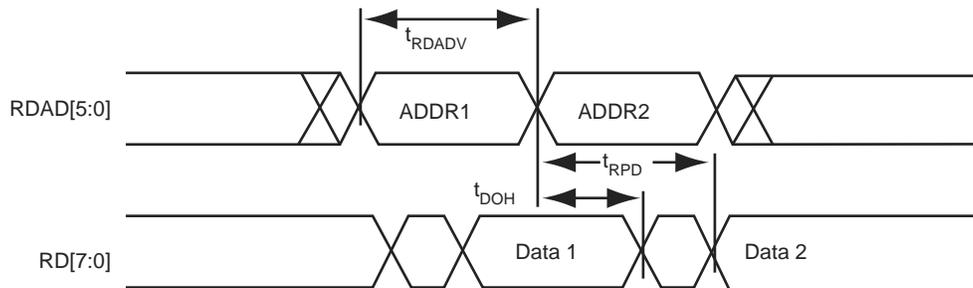


Table 33 • Timing Parameters for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
$t_{SU(PTP)}$	Input Set-Up Time to CLK—Point-to-Point	10, 12 ²	–	1.5	–	1.5	–	ns
t_H	Input Hold to CLK	0	–	0	–	0	–	ns

1. TOFF is system dependent. MX PCI devices have 7.4 ns turn-off time, reflection is typically an additional 10 ns.
2. REQ# and GNT# are point-to-point signals and have different output valid delay and input setup times than do bussed signals. GNT# has a setup of 10; REW# has a setup of 12.

3.11.6.1 Timing Characteristics

The following tables list the timing characteristics.

**Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation)
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)**

Parameter / Description	–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units	
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t_{PD2}	Dual-Module Macros		2.7		3.1		3.5		4.1		5.7	ns
t_{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays¹												
t_{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.8	ns
t_{RD2}	FO = 2 Routing Delay		1.8		2.1		2.4		2.8		3.9	ns
t_{RD3}	FO = 3 Routing Delay		2.3		2.7		3.0		3.6		5.0	ns
t_{RD4}	FO = 4 Routing Delay		2.9		3.3		3.7		4.4		6.1	ns
t_{RD8}	FO = 8 Routing Delay		4.9		5.7		6.5		7.6		10.6	ns
Logic Module Sequential Timing²												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up		3.1		3.5		4.0		4.7		6.6	ns
t_{HD}^3	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up		3.1		3.5		4.0		4.7		6.6	ns
t_{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0	ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		3.3		3.8		4.3		5.0		7.0	ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		3.3		3.8		4.3		5.0		7.0	ns
t_A	Flip-Flop Clock Input Period		4.8		5.6		6.3		7.5		10.4	ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		181		168		154		134		80	MHz

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing¹											
t _{DLH}	Data-to-Pad HIGH	3.9	4.5	5.1	6.05	8.5	ns				
t _{DHL}	Data-to-Pad LOW	3.4	3.9	4.4	5.2	7.3	ns				
t _{ENZH}	Enable Pad Z to HIGH	3.4	3.9	4.4	5.2	7.3	ns				
t _{ENZL}	Enable Pad Z to LOW	4.9	5.6	6.4	7.5	10.5	ns				
t _{ENHZ}	Enable Pad HIGH to Z	7.9	9.1	10.4	12.2	17.0	ns				
t _{ENLZ}	Enable Pad LOW to Z	5.9	6.8	7.7	9.0	12.6	ns				
d _{TLH}	Delta LOW to HIGH	0.03	0.04	0.04	0.05	0.07	ns/pF				
d _{THL}	Delta HIGH to LOW	0.02	0.02	0.03	0.03	0.04	ns/pF				

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer utility from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays											
t _{PD1}	Single Module	1.7	2.0	2.3	2.7	3.7	ns				
t _{PD2}	Dual-Module Macros	3.7	4.3	4.9	5.7	8.0	ns				
t _{CO}	Sequential Clock-to-Q	1.7	2.0	2.3	2.7	3.7	ns				
t _{GO}	Latch G-to-Q	1.7	2.0	2.3	2.7	3.7	ns				
t _{RS}	Flip-Flop (Latch) Reset-to-Q	1.7	2.0	2.3	2.7	3.7	ns				
Logic Module Predicted Routing Delays¹											
t _{RD1}	FO = 1 Routing Delay	1.9	2.2	2.5	3.0	4.2	ns				
t _{RD2}	FO = 2 Routing Delay	2.7	3.1	3.5	4.1	5.7	ns				
t _{RD3}	FO = 3 Routing Delay	3.4	3.9	4.4	5.2	7.3	ns				
t _{RD4}	FO = 4 Routing Delay	4.1	4.8	5.4	6.3	8.9	ns				
t _{RD8}	FO = 8 Routing Delay	7.1	8.1	9.2	10.9	15.2	ns				
Logic Module Sequential Timing²											
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	4.3	5.0	5.6	6.6	9.2	ns				
t _{HD} ³	Flip-Flop (Latch) Data Input Hold	0.0	0.0	0.0	0.0	0.0	ns				
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	4.3	5.0	5.6	6.6	9.2	ns				
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0	0.0	0.0	0.0	0.0	ns				

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WCLKA} Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _A Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f _{MAX} Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
Input Module Propagation Delays											
t _{INYH} Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t _{INYL} Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing⁵											
t _{DLH}	Data-to-Pad HIGH	3.4	3.8	4.3	5.1	6.1	7.1	ns			
t _{DHL}	Data-to-Pad LOW	4.0	4.5	5.1	6.1	8.3	ns				
t _{ENZH}	Enable Pad Z to HIGH	3.7	4.1	4.6	5.5	7.6	ns				
t _{ENZL}	Enable Pad Z to LOW	4.1	4.5	5.1	6.1	8.5	ns				
t _{ENHZ}	Enable Pad HIGH to Z	6.9	7.6	8.6	10.2	14.2	ns				
t _{ENLZ}	Enable Pad LOW to Z	7.5	8.3	9.4	11.1	15.5	ns				
t _{GLH}	G-to-Pad HIGH	5.8	6.5	7.3	8.6	12.0	ns				
t _{GHL}	G-to-Pad LOW	5.8	6.5	7.3	8.6	12.0	ns				
t _{LSU}	I/O Latch Set-Up	0.7	0.8	0.9	1.0	1.4	ns				
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns				
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading	8.7	9.7	10.9	12.9	18.0	ns				
t _{ACO}	Array Clock-to-Out (Pad-to-Pad),64 Clock Loading	12.2	13.5	15.4	18.1	25.3	ns				
d _{TLH}	Capacity Loading, LOW to HIGH	0.00	0.00	0.00	0.10	0.01	ns/pF				
d _{THL}	Capacity Loading, HIGH to LOW	0.09	0.10	0.10	0.10	0.10	ns/pF				

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing⁵											
t _{DLH}	Data-to-Pad HIGH	3.5	3.9	4.5	5.2	7.3	ns				
t _{DHL}	Data-to-Pad LOW	2.5	2.7	3.1	3.6	5.1	ns				
t _{ENZH}	Enable Pad Z to HIGH	2.7	3.0	3.3	3.9	5.5	ns				
t _{ENZL}	Enable Pad Z to LOW	2.9	3.3	3.7	4.3	6.1	ns				
t _{ENHZ}	Enable Pad HIGH to Z	5.3	5.8	6.6	7.8	10.9	ns				
t _{ENLZ}	Enable Pad LOW to Z	4.9	5.5	6.2	7.3	10.2	ns				
t _{GLH}	G-to-Pad HIGH	5.0	5.6	6.3	7.5	10.4	ns				
t _{GHL}	G-to-Pad LOW	5.0	5.6	6.3	7.5	10.4	ns				
t _{LSU}	I/O Latch Set-Up	0.5	0.5	0.6	0.7	1.0	ns				
t _{LH}	I/O Latch Hold	0.0	0.0	0.0	0.0	0.0	ns				
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O	5.7	6.3	7.1	8.4	11.8	ns				
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O	7.8	8.6	9.8	11.5	16.1	ns				
d _{TLH}	Capacitive Loading, LOW to HIGH	0.07	0.08	0.09	0.10	0.14	ns/pF				
d _{THL}	Capacitive Loading, HIGH to LOW	0.07	0.08	0.09	0.10	0.14	ns/pF				

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions¹											
t _{PD}	Internal Array Module Delay	1.9	2.1	2.3	2.7	3.8	ns				
t _{PDD}	Internal Decode Module Delay	2.2	2.5	2.8	3.3	4.7	ns				
Logic Module Predicted Routing Delays²											
t _{RD1}	FO = 1 Routing Delay	1.3	1.5	1.7	2.0	2.7	ns				
t _{RD2}	FO = 2 Routing Delay	1.8	2.0	2.3	2.7	3.7	ns				
t _{RD3}	FO = 3 Routing Delay	2.3	2.5	2.8	3.4	4.7	ns				
t _{RD4}	FO = 4 Routing Delay	2.8	3.1	3.5	4.1	5.7	ns				

Table 47 • PL44

PL44		
Pin Number	A40MX02 Function	A40MX04 Function
21	GND	GND
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	CLK, I/O	CLK, I/O
34	MODE	MODE
35	VCC	VCC
36	SDI, I/O	SDI, I/O
37	DCLK, I/O	DCLK, I/O
38	PRA, I/O	PRA, I/O
39	PRB, I/O	PRB, I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	GND	GND
44	I/O	I/O

Figure 42 • PQ144

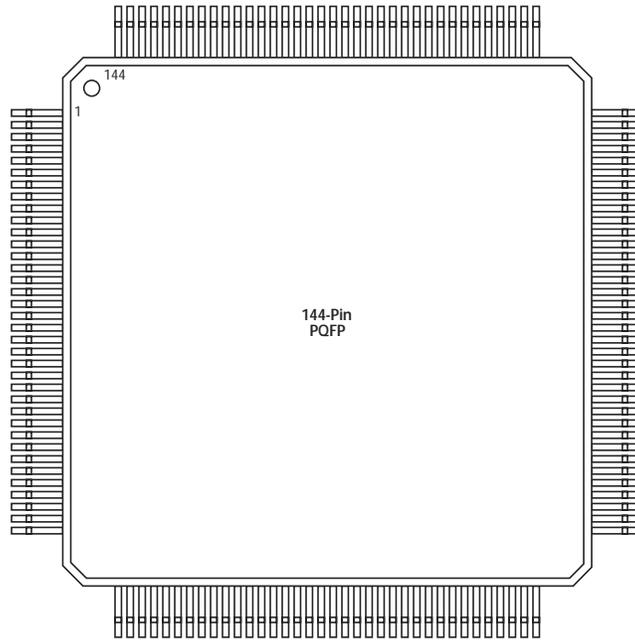


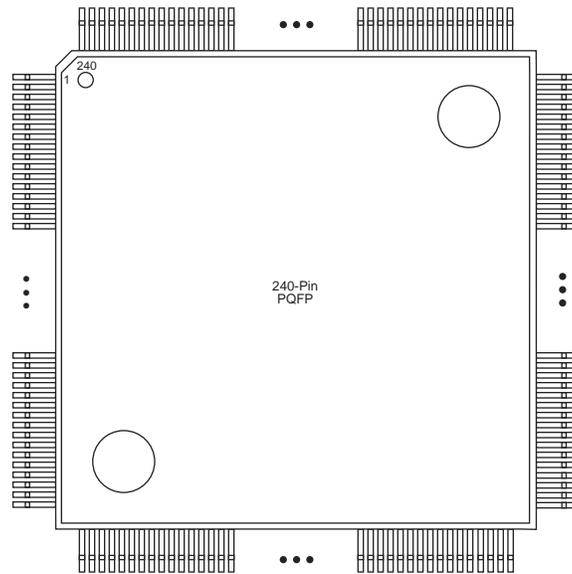
Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
206	I/O	I/O	I/O
207	DCLK, I/O	DCLK, I/O	DCLK, I/O
208	I/O	I/O	I/O

Figure 45 • PQ240



Note: This figure shows the 240-Pin PQFP Package top view.

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
1	I/O
2	DCLK, I/O
3	I/O
4	I/O
5	I/O
6	WD, I/O
7	WD, I/O
8	VCCI
9	I/O
10	I/O
11	I/O
12	I/O
13	I/O
14	I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCCA	VCCA
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	GND	GND
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	I/O	I/O
50	SDO, I/O	SDO, I/O
51	I/O	I/O
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	GND	GND
56	I/O	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
158	CLKB, I/O	CLKB, I/O	CLKB, I/O
159	I/O	I/O	I/O
160	PRB, I/O	PRB, I/O	PRB, I/O
161	NC	I/O	WD, I/O
162	I/O	I/O	WD, I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	NC	NC	WD, I/O
166	NC	I/O	WD, I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	I/O	I/O	I/O
170	NC	VCCI	VCCI
171	I/O	I/O	WD, I/O
172	I/O	I/O	WD, I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	DCLK, I/O	DCLK, I/O	DCLK, I/O
176	I/O	I/O	I/O

Figure 49 • CQ208

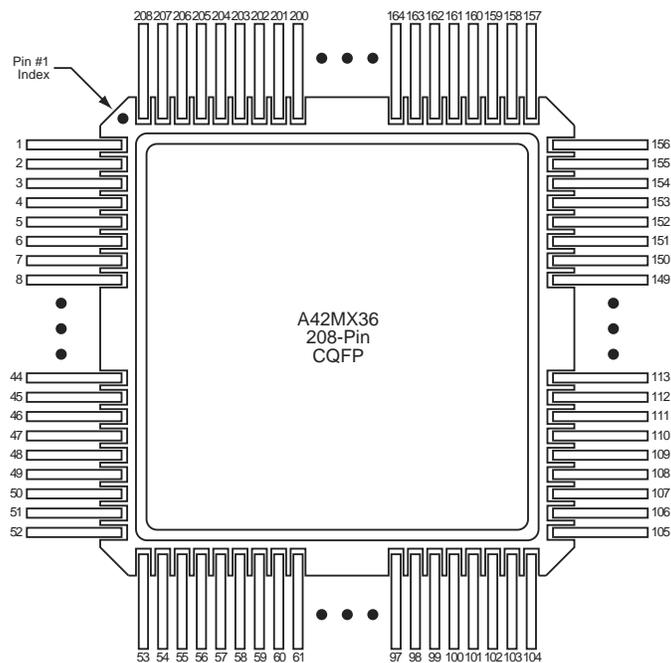


Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
74	I/O
75	I/O
76	I/O
77	I/O
78	GND
79	VCCA
80	VCCI
81	I/O
82	I/O
83	I/O
84	I/O
85	WD, I/O
86	WD, I/O
87	I/O
88	I/O
89	I/O
90	I/O
91	QCLKB, I/O
92	I/O
93	WD, I/O
94	WD, I/O
95	I/O
96	I/O
97	I/O
98	VCCI
99	I/O
100	WD, I/O
101	WD, I/O
102	I/O
103	TDO, I/O
104	I/O
105	GND
106	VCCA
107	I/O
108	I/O
109	I/O
110	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
M10	GND
M11	GND
M12	GND
M17	I/O
M18	I/O
M19	I/O
M20	I/O
N1	I/O
N2	I/O
N3	I/O
N4	VCCI
N17	VCCI
N18	I/O
N19	I/O
N20	I/O
P1	I/O
P2	I/O
P3	I/O
P4	VCCA
P17	I/O
P18	I/O
P19	I/O
P20	I/O
R1	I/O
R2	I/O
R3	I/O
R4	VCCI
R17	VCCI
R18	I/O
R19	I/O
R20	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T17	VCCA
T18	I/O